

Refine Search

Search Results -

Term	Documents
(18 NOT 16).PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD.	94
(L18 NOT L16).PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD.	94

Database: US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Search: L20

Search History

DATE: Friday, August 20, 2004 [Printable Copy](#) [Create Case](#)

Set	Name	Query	Hit Count	Set Name result set
side by side				
		DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR		
<u>L20</u>	<u>l18</u>	not <u>l16</u>	94	<u>L20</u>
<u>L19</u>		<u>l15</u> and (add\$5 or calculat\$4 or comput\$3) near5 count\$3 near8 (decod\$3 or map\$4 or table)	5	<u>L19</u>
<u>L18</u>		<u>l15</u> and (add\$5 or calculat\$4 or comput\$3) near5 count\$3	101	<u>L18</u>
<u>L17</u>		<u>L14</u> and <u>l6</u>	3	<u>L17</u>
<u>L16</u>		<u>L14</u> and <u>l5</u>	49	<u>L16</u>
<u>L15</u>		<u>L14</u> and <u>l3</u>	167	<u>L15</u>
<u>L14</u>		<u>L13</u> and decod\$3 near7 (bit\$1 or length or width or size or word\$1 or byte\$1) L10 and (id\$1 or identification\$1 or identify\$5) near5 register\$1 near15 (bit\$1 or position\$1) and transfer\$6 near6 (data or block\$1 or group\$1 or byte\$1 or word\$1 or portion\$1 or segment\$1 or bit\$1)	510	<u>L14</u>
<u>L13</u>			838	<u>L13</u>
<u>L12</u>		<u>L11</u> and <u>l3</u>	202	<u>L12</u>

Best Available Copy

<u>L11</u>	L10 and (id\$1 or identification\$1 or identify\$5) near5 register\$1 near15 (bit\$1 or position\$1)	1011	<u>L11</u>
<u>L10</u>	(start\$3 or initial\$4) near5 count\$3 and (id\$1 or identification\$1 or identify\$5) near5 register\$1	3492	<u>L10</u>
<i>DB=PGPB,USPT; PLUR=YES; OP=OR</i>			
<u>L9</u>	l1 and l6	0	<u>L9</u>
<u>L8</u>	l1 and l5	2	<u>L8</u>
<u>L7</u>	l1 and l3	2	<u>L7</u>
<u>L6</u>	(710/34)![CCLS]	163	<u>L6</u>
<u>L5</u>	(710/2-74)![CCLS]	11204	<u>L5</u>
<u>L4</u>	(712/3-300)[CCLS]	10134	<u>L4</u>
<u>L3</u>	(712/3-300)![CCLS]	10134	<u>L3</u>
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>			
<u>L2</u>	(start\$3 or initial\$4) near5 count\$3 near15 (id\$1 or identification\$1 or identify\$5) near5 register\$1 near15 (bit\$1 or position\$1)	10	<u>L2</u>
<u>L1</u>	(start\$3 or initial\$4) near5 count\$3 near15 (id\$1 or identification\$1 or identify\$5) near5 register\$1	53	<u>L1</u>

END OF SEARCH HISTORY



» See

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

 Print Format

Your search matched **7 of 1062489** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

count and register and (identification or id or identify)

Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 A new approach to the design of built-in self-testing PLAs for high f coverage

Upadhyaya, S.J.; Saluja, K.K.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction on, Volume: 7, Issue: 1, Jan. 1988
Pages:60 - 67

[\[Abstract\]](#) [\[PDF Full-Text \(788 KB\)\]](#) **IEEE JNL**

2 An extended addressing mode for low power

Kalambur, A.; Irwin, M.J.;

Low Power Electronics and Design, 1997. Proceedings., 1997 International Symposium on, 18-20 Aug. 1997
Pages:208 - 213

[\[Abstract\]](#) [\[PDF Full-Text \(504 KB\)\]](#) **IEEE CNF**

3 Inter-cluster communication models for clustered VLIW processors

Terechko, A.; Le Thenaff, E.; Garg, M.; van Eijndhoven, J.; Corporaal, H.;

The Ninth International Symposium on High-Performance Computer Architect 2003. HPCA-9 2003. Proceedings., 8-12 Feb. 2003
Pages:354 - 364

[\[Abstract\]](#) [\[PDF Full-Text \(371 KB\)\]](#) **IEEE CNF**

4 Elastic minutiae matching by means of thin-plate spline models

Bazen, A.M.; Gerez, S.H.;

Pattern Recognition, 2002. Proceedings. 16th International Conference on, Volume: 2, 11-15 Aug. 2002
Pages:985 - 988 vol.2

Best Available Copy

[\[Abstract\]](#) [\[PDF Full-Text \(351 KB\)\]](#) [IEEE CNF](#)

5 Analysis of scanners for TFT-LCD

Fleischer, D.L.; Hatalis, M.K.;

Active Matrix Liquid Crystal Displays, 1995. AMLCDs '95., Second International Workshop on, 25-26 Sept. 1995

Pages:76 - 79

[\[Abstract\]](#) [\[PDF Full-Text \(220 KB\)\]](#) [IEEE CNF](#)

6 A case study of functional design using functional simulation and logic synthesis

Takei, T.; Sekine, M.; Nishi, H.; Kitahara, T.; Masuda, A.;

ASIC Seminar and Exhibit, 1989. Proceedings., Second Annual IEEE, 25-28 Sept. 1989

Pages:P2 - 1/1-4

[\[Abstract\]](#) [\[PDF Full-Text \(352 KB\)\]](#) [IEEE CNF](#)

7 Aliasing errors in signature analysis testing of integrated circuits

Damiani, M.; Olivo, P.; Favalli, M.; Ricco, B.;

Computer Design: VLSI in Computers and Processors, 1988. ICCD '88., Proceedings of the 1988 IEEE International Conference on, 3-5 Oct. 1988

Pages:458 - 461

[\[Abstract\]](#) [\[PDF Full-Text \(288 KB\)\]](#) [IEEE CNF](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

Best Available Copy



IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Membership Publications/Services Standards Conferences Careers/Jobs



Welcome
United States Patent and Trademark Office



» Se...

Help FAQ Terms IEEE Peer Review

Quick Links

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

Best Available Copy